



Nanoscale characterization with scattering-type scanning near- field infrared microscopy

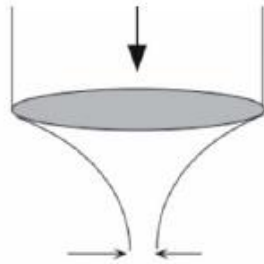
Gergely Németh

Supervisors: Katalin Kamarás, Áron Pekker

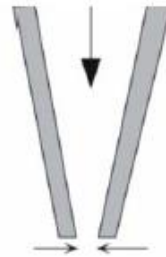
Outline

- Motivation, why do we need near fields?
- Principles of s-SNOM technique
- Measurements on carbon nanotubes and hybrid systems

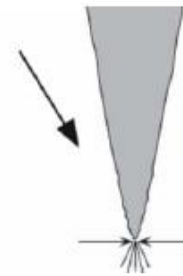
Spatial resolution in classical microscopy and in near-field techniques



classical
diffraction-limited
Airy-spot



aperture SNOM
aperture-limited



scattering SNOM
tip-limited

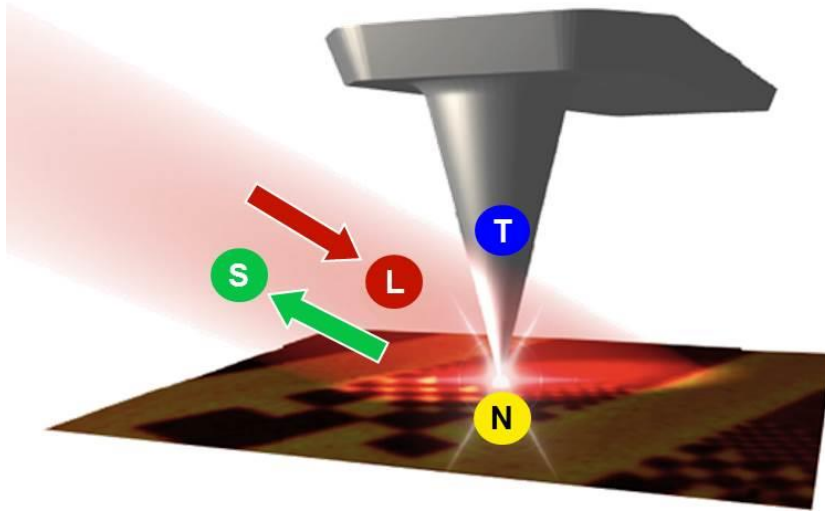
$$\lambda \approx 10\mu m \rightarrow \Delta x = \frac{0.61\lambda}{n \cdot \sin(\theta)} \approx 5\mu m$$

-metal-coated optical fiber
 $d < \frac{\lambda}{2}$ - T drops down dramatically

e.g. $\lambda \approx 10\mu m$ $d = 100nm$
Transmission: 10^{-25}

Resolution: $\Delta x > \frac{\lambda}{10} \approx 1 - 2 \mu m$

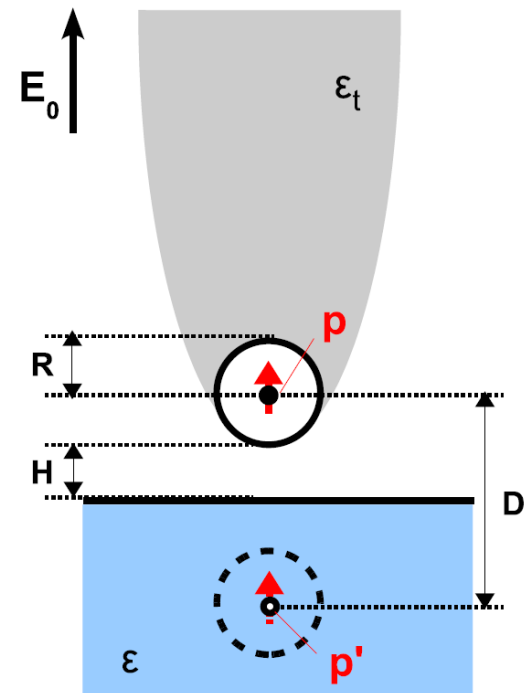
s-SNOM principles



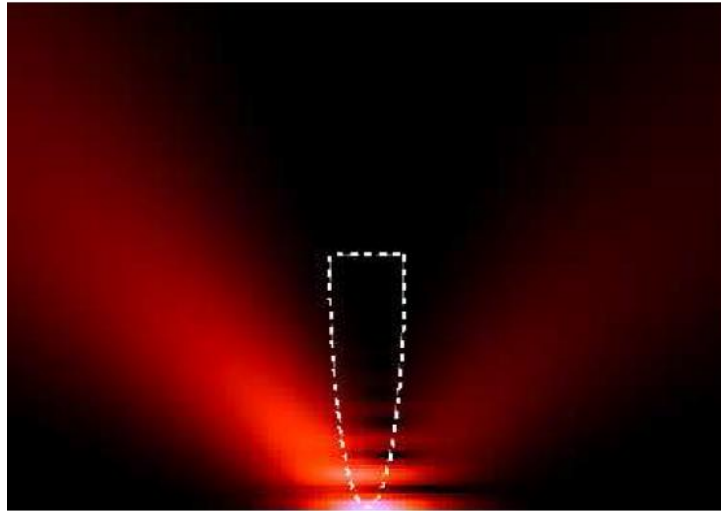
$$E_s = \sigma E_0 \quad \sigma = s \cdot e^{i\varphi}$$

- Metal-coated AFM tip
- Evanescent EM field at a apex of the tip
- Very close to the sample
- Near field polarizes the sample
- Interaction results scattered EM waves

- $\lambda_0 \gg$ characteristic sizes of the tip
- Electrostatic problem at each timestep
- Incoming light is polarized parallel to the tip axis
- $p = \alpha \cdot E_0$ - induced dipole moment in the tip
- Mirror dipole in the sample: $p' = \beta p \rightarrow \beta = \frac{\epsilon - 1}{\epsilon + 1}$

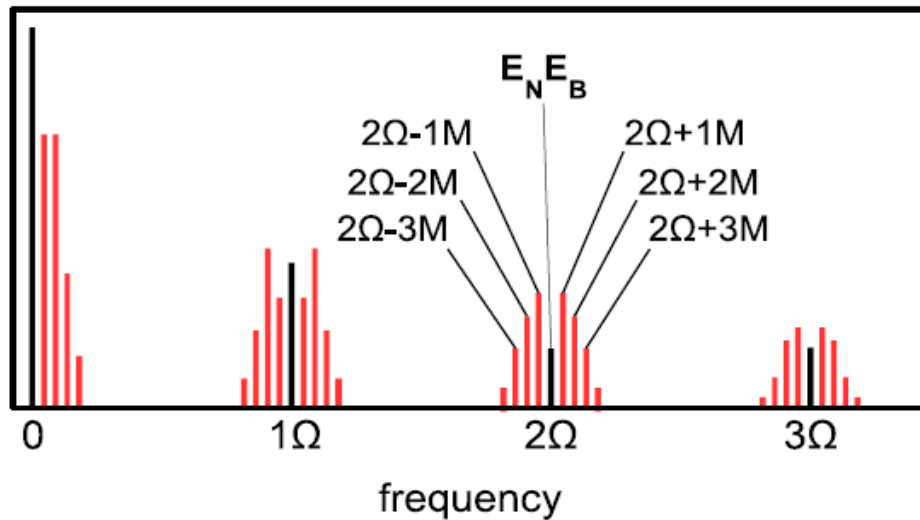
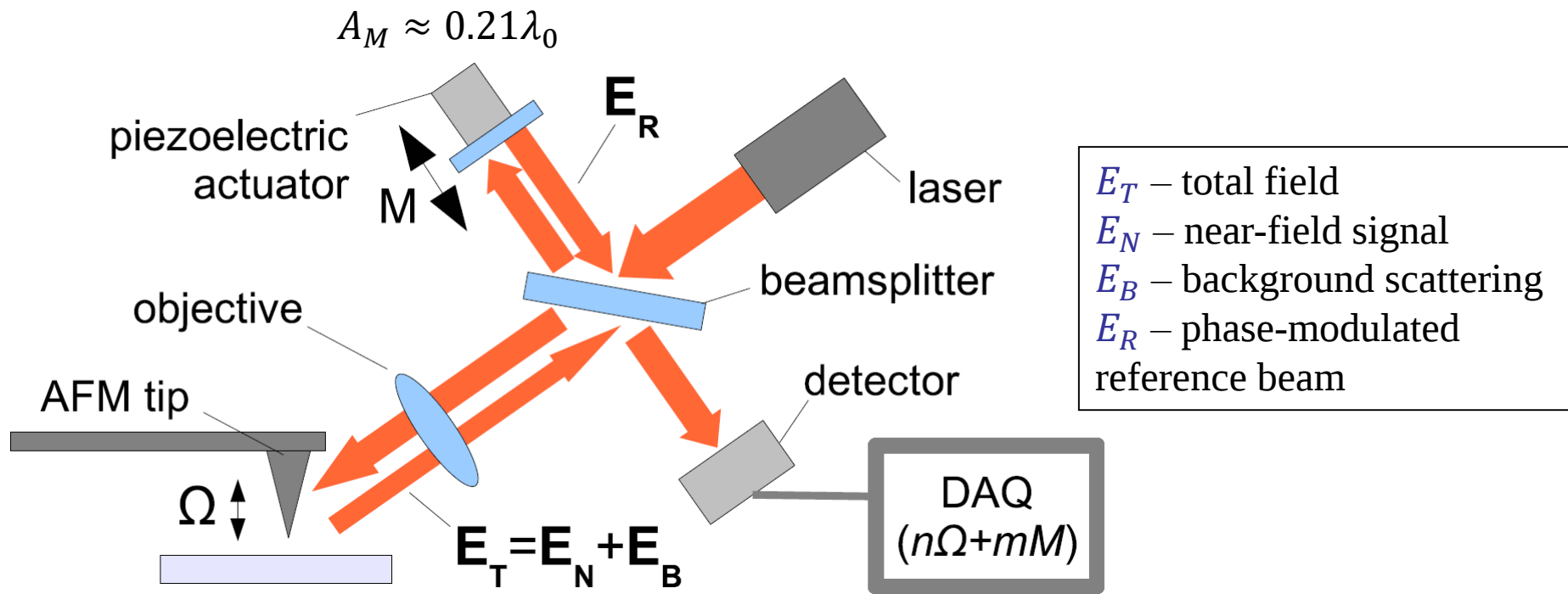


- Only a small part of the detected light originates from the near-field interaction
- Airy spot is few microns, near-field volume is few of 10 nm-s
 - Background: direct scattering from tip shaft, reflection, scattering from surface roughness
 - Incoming + reflected beam $\rightarrow$ interference $\rightarrow$ standing waves



Solution: AFM works in tapping mode at Ω frequency + demodulation @ $n\Omega$

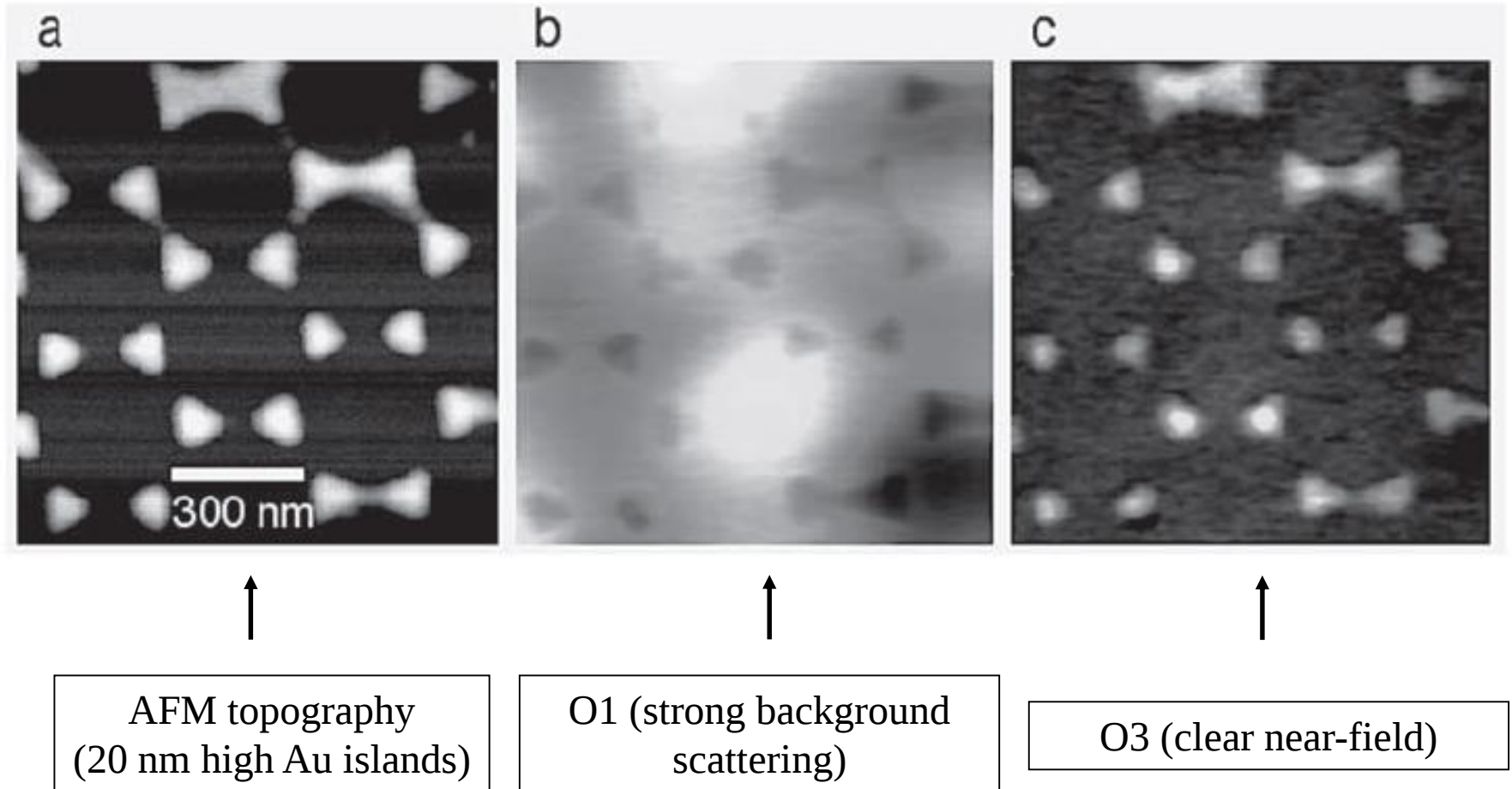
$$I = (E_B + E_N)^2 \quad \Rightarrow \quad \cancel{E_B^2} + E_N^2 + 2E_N E_B \quad \leftarrow \text{still contains } E_B$$



$$s_n = \sqrt{|C_{n\Omega+M}|^2 + |C_{n\Omega+2M}|^2}$$

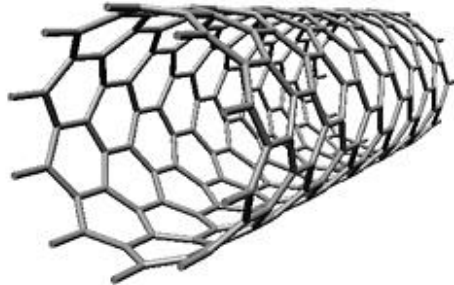
$$\varphi_n = \arctan \frac{|C_{n\Omega+M}|}{|C_{n\Omega+2M}|}$$

Demodulation at higher harmonics



Study on single-walled carbon nanotubes

Single-walled CNT

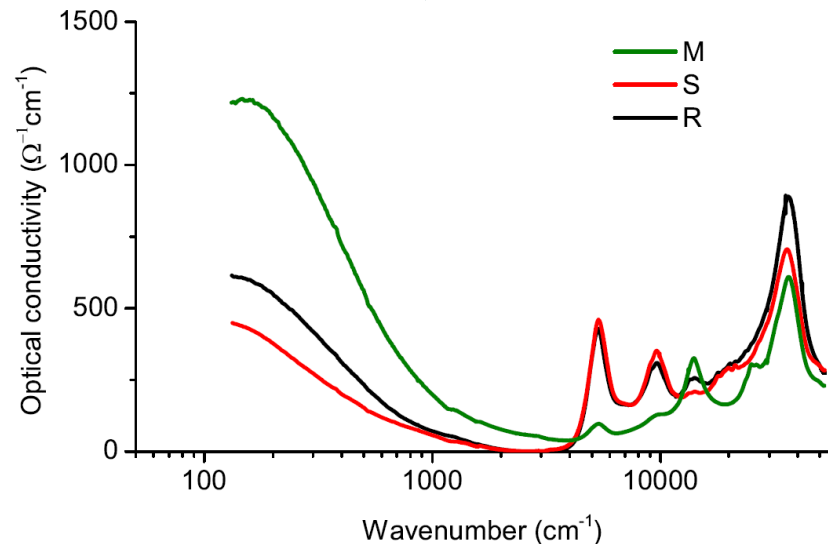
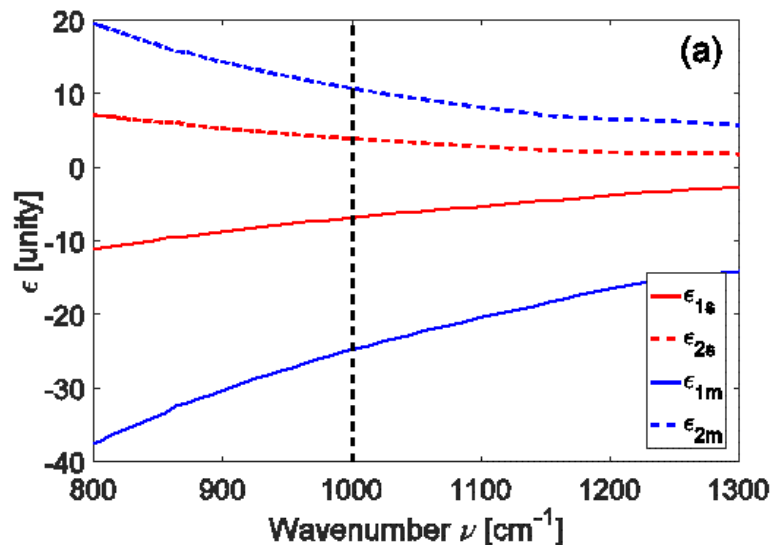


Properties are defined by their structure

- Semiconducting
- Metallic

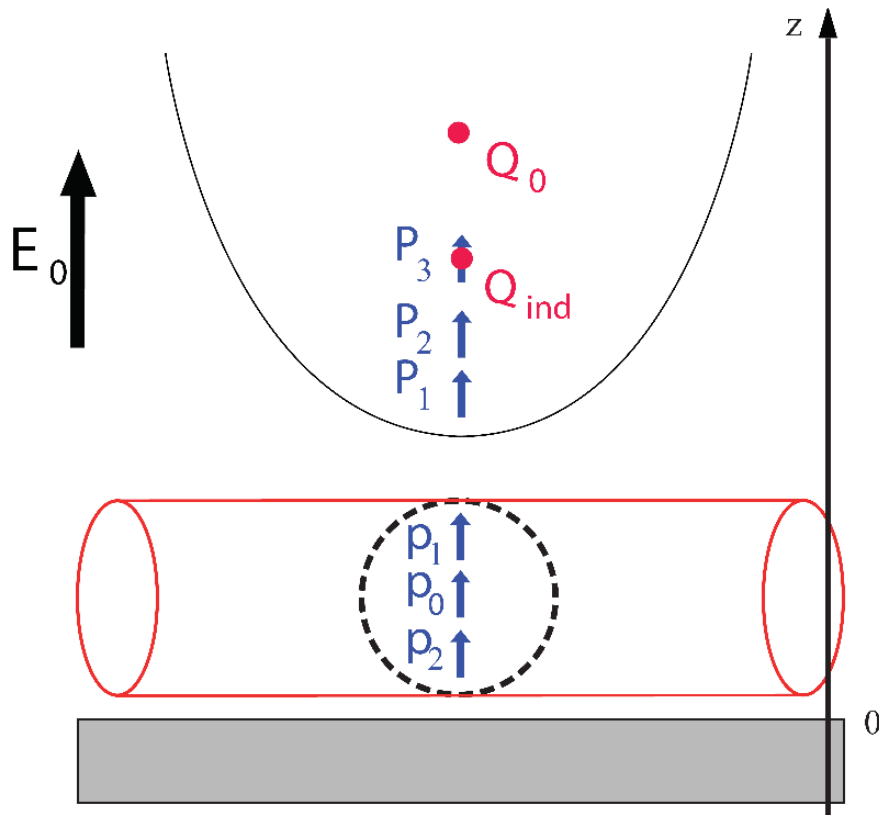
Selective production is important

- Qualify these methods
- Different optical properties



Analytical model

Analytical calculations based on extended finite dipole model (EFDM)



- Substrate-particle-tip system
- Approximated with numerous charges generated by the incident E field
- p_0, p_1, p_2 describe electric field of the nanoparticle
- $p = \alpha_z \cdot E_{loc}$
- Nanotubes are cylinder-like objects
- Approximated with a prolate ellipsoid
- The following expression was used:

$$\alpha_z = \frac{\epsilon - 1}{1 + N_z(\epsilon + 1)}$$

$\epsilon = \epsilon_1 + i \cdot \epsilon_2$ - complex dielectric function

N_z - depolarization factor

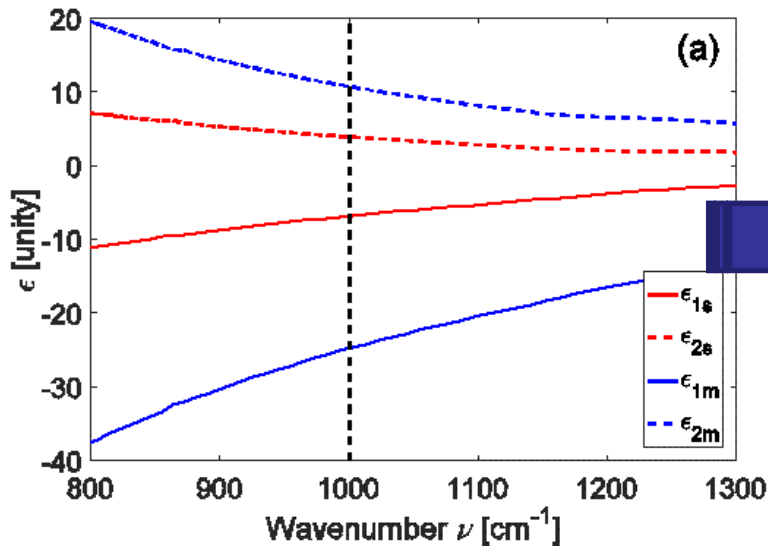
$$p_{eff} = -2Q_0L - Q_{ind}L + P_1 + P_2 + P_3 + p_0 + p_1 + p_2$$

$$p_{eff} \propto \sigma$$

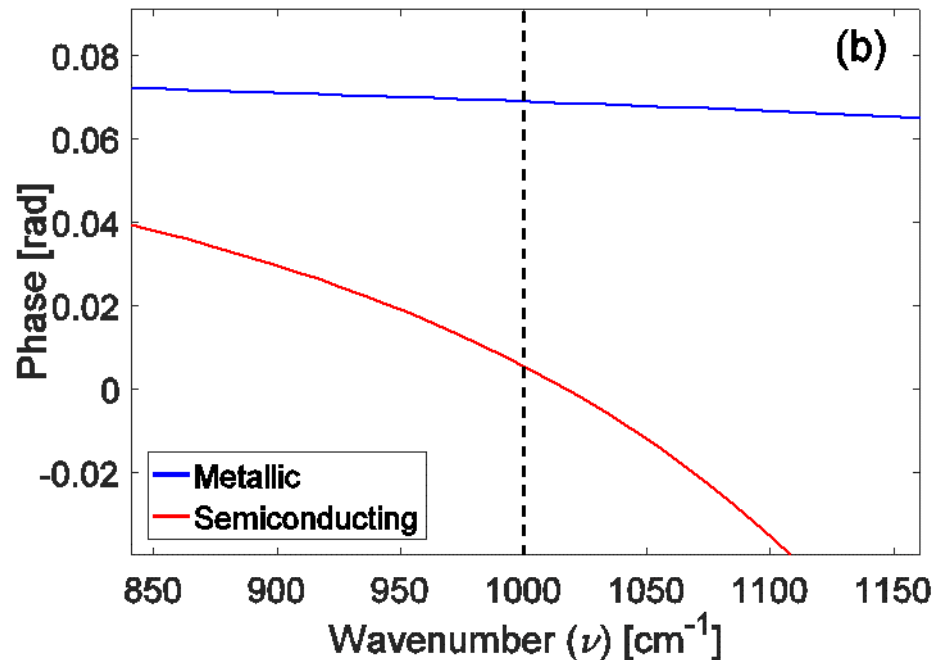
Simulating the tapping mode: $z = (H + A(1 - \cos(\Omega t))) \rightarrow \text{demodulation} \rightarrow \sigma_n = s_n e^{i\varphi_n}$

Analytical calculations

Complex dielectric function of SWCNTs from Kramers-Kronig analysis

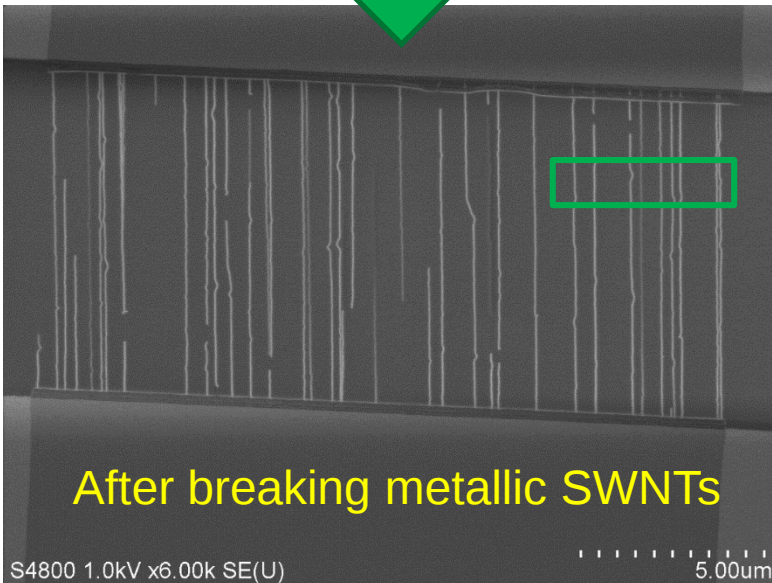
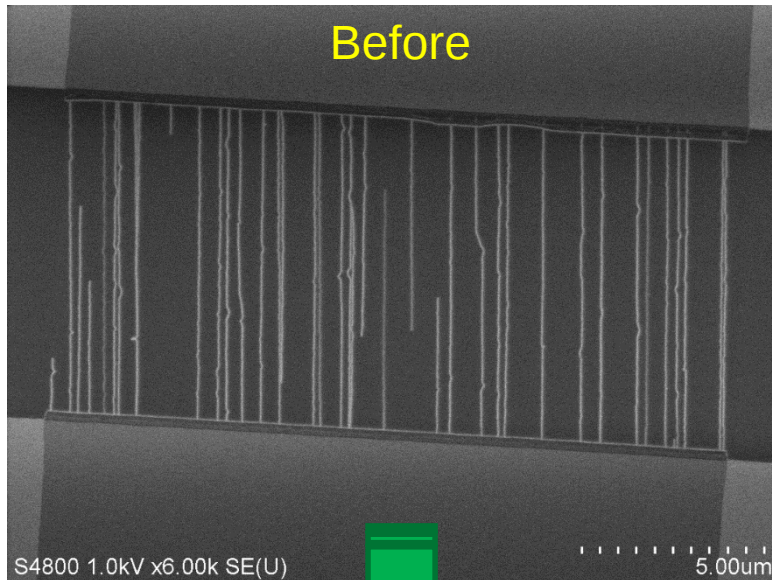


Third harmonic phase of d=4 nm bundles



Phase data are normalized to the Si substrate

Aligned SWCNT samples

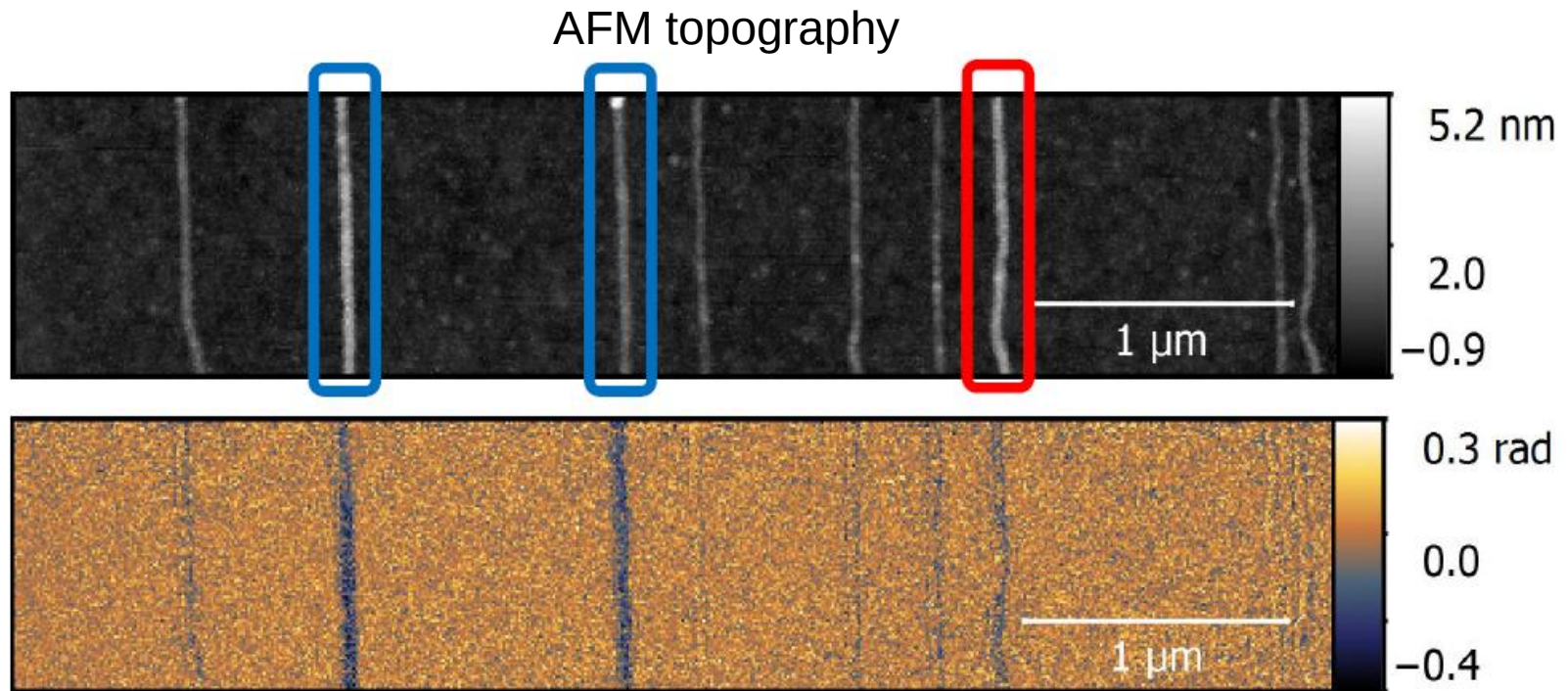


- CNT array for transistor fabrication
- Samples from University of Tokyo
- Group of Prof. Shigeo Maruyama
- Horizontally aligned nanotubes grown by CVD
- Transferred onto Si/SiO₂ substrate
- Gold contacts
- Metallic nanotubes were destroyed
 - Electrical breakdown technique

K. Otsuka, T. Inoue, S. Chiashi, and S. Maruyama, *Nanoscale* 6, 8831 (2014).

P. G. Collins, M. S. Arnold, P. Avouris, *Science* 292, 706-709 (2001).

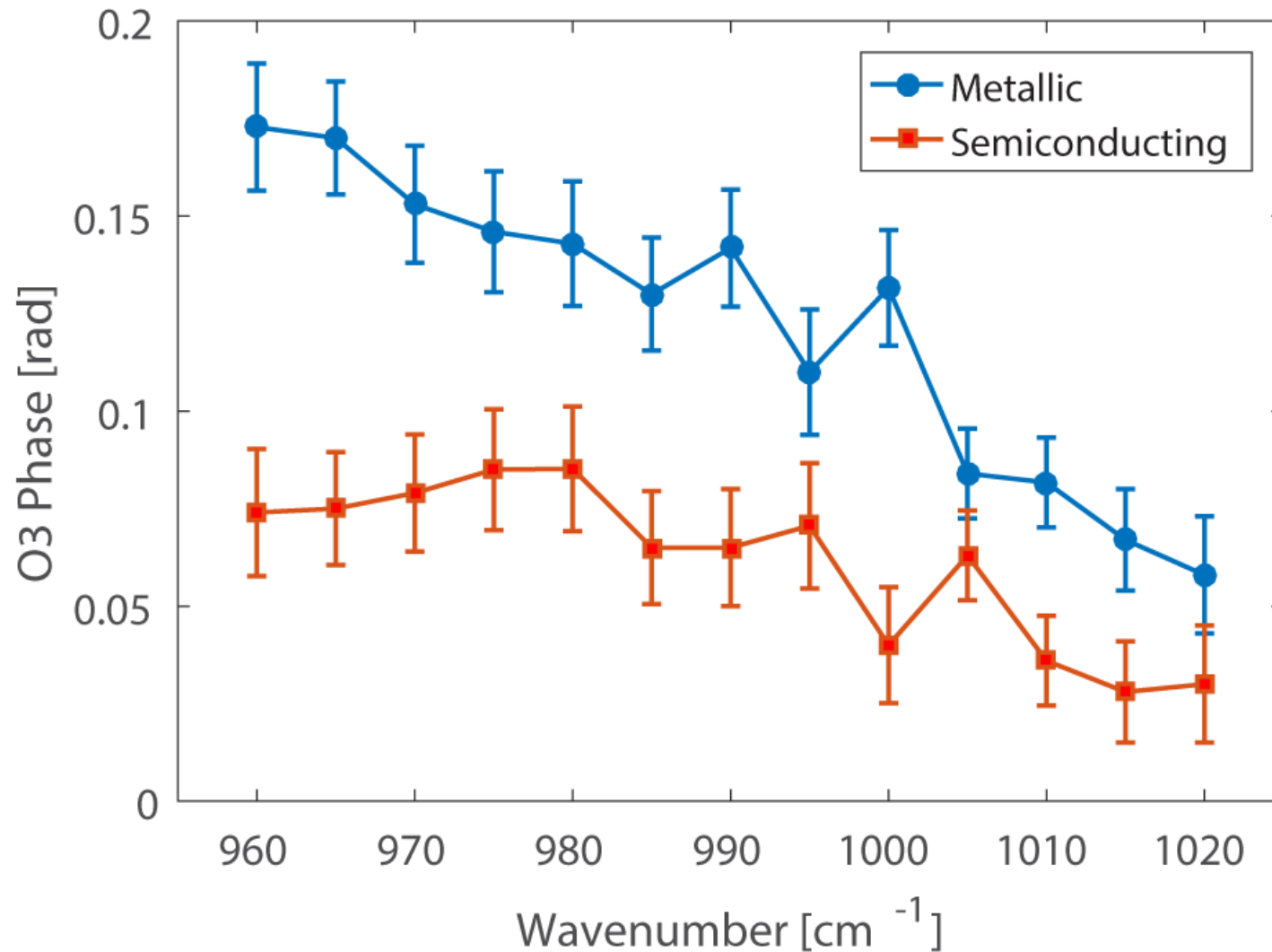
Results on individual nanotubes



O3 demodulated near-field phase map

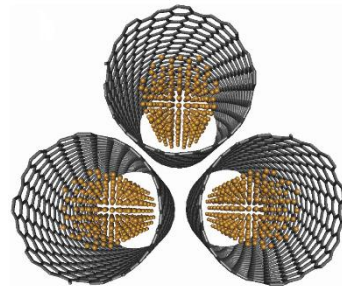
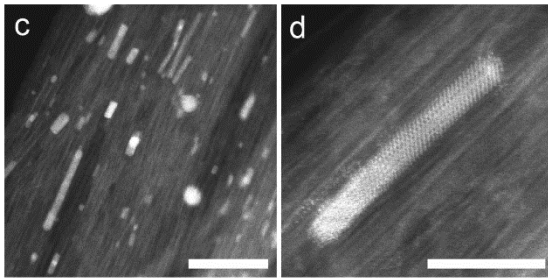
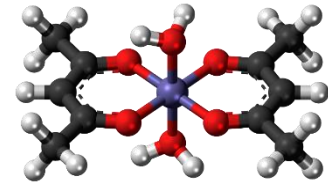
- Diameter of the metallic tubes:
 - $d_1 \approx 3 \text{ nm}$ and $d_2 \approx 1.7 \text{ nm}$
- Optical response:
 - $\varphi_{O3} \approx 0.168 \text{ [rad]}$ and $\varphi_{O3} \approx 0.132 \text{ [rad]}$
- Largest semiconducting tube:
 - $d \approx 2.5 \text{ nm}$
- Optical response:
 - $\varphi_{O3} \approx 0.06 \text{ [rad]}$

Spectral behaviour of individual tubes

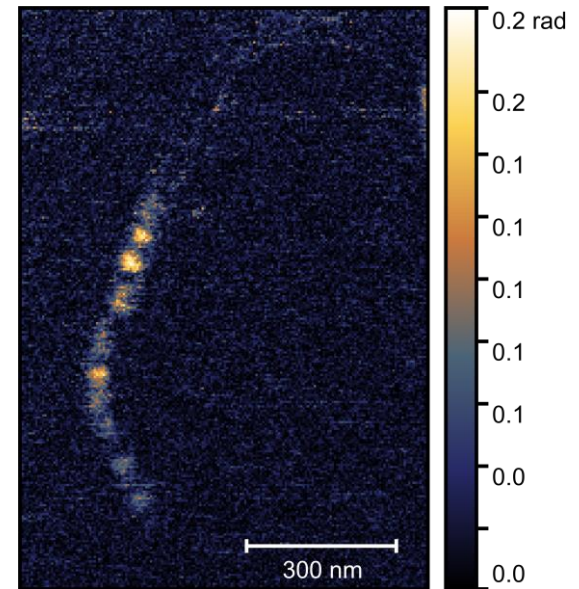


Hybrid nanotube systems

- eDip single-walled carbon nanotubes filled with Nickel(II) acetylacetonate (NiACAC)
- The molecules encapsulated inside SWCNTs can be transformed by heating in vacuum to metal clusters

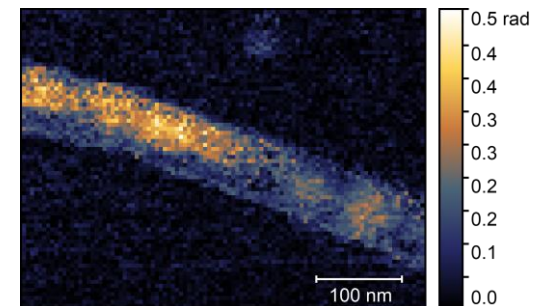
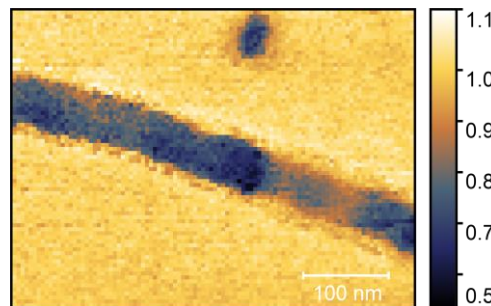
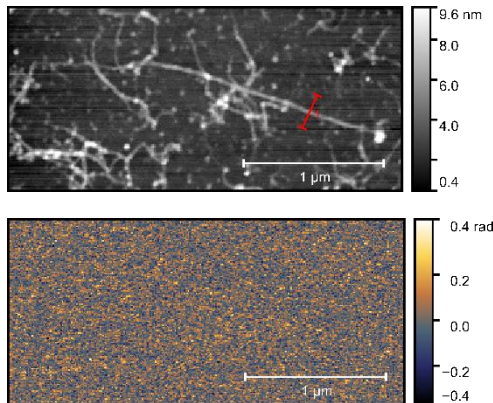


- Theoretical predictions: Ni clusters can locally influence near-field phase with their extra dipole moments



After heating

Before heating



Conclusions

Spatial resolution $\approx 10 - 20nm$

Sensitivity level is much higher $\approx 1nm \rightarrow SWCNTs$

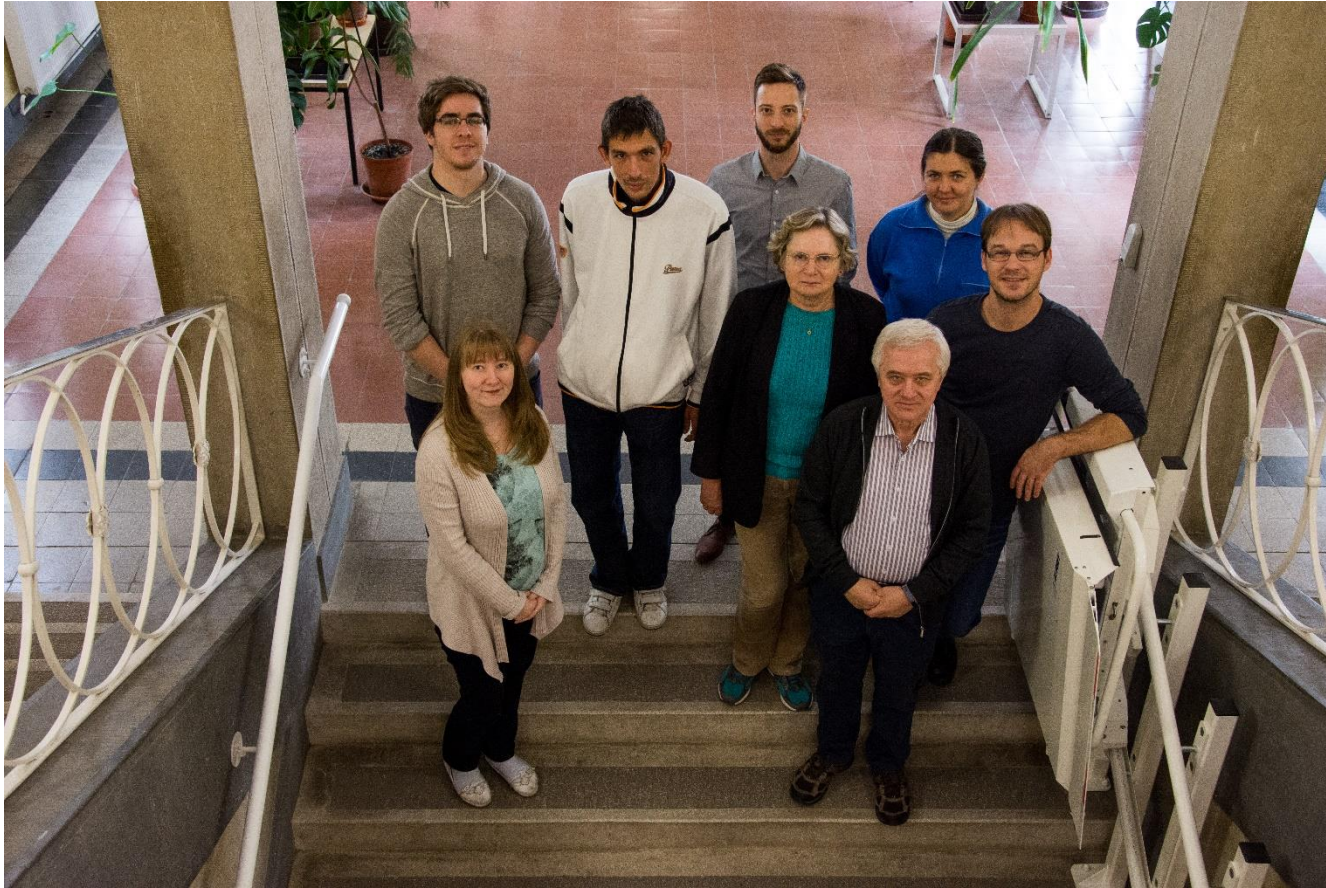
Signal from difference in polarizability $\rightarrow$ many different sources

- Collective excitations $\rightarrow$ BNNTs
- Molecular vibrations
- Charge density difference
- Material specific recognition

Huge variability and possibilities

- We are open for collaboration

Acknowledgement



BME

- Koppa Pál
- Sepsi Örs

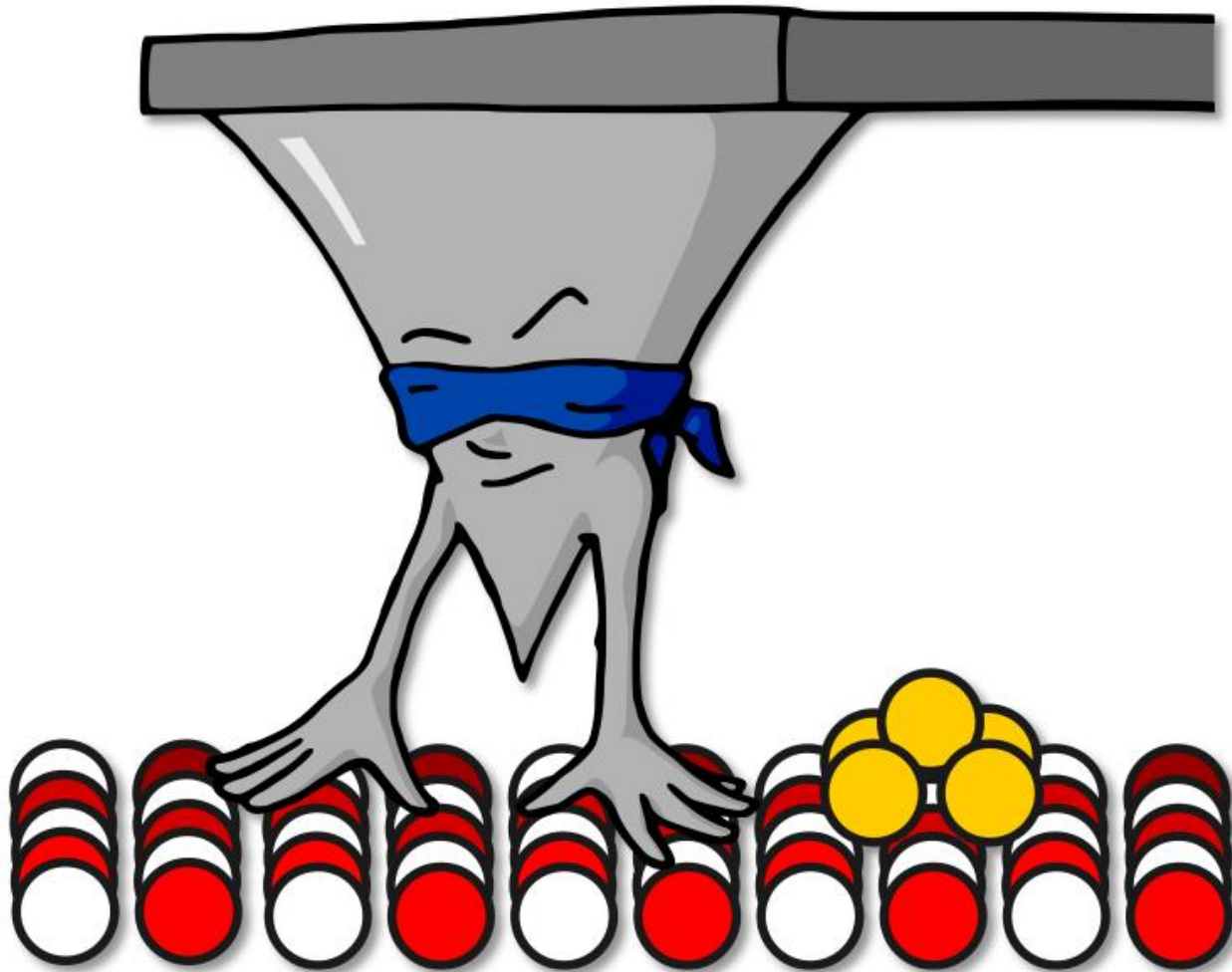
University of Tokyo

- Group of Prof. Shigeo Maruyama

University of Nottingham

- Group of Prof. Andrei N. Khlobystov

Thank you for your attention!



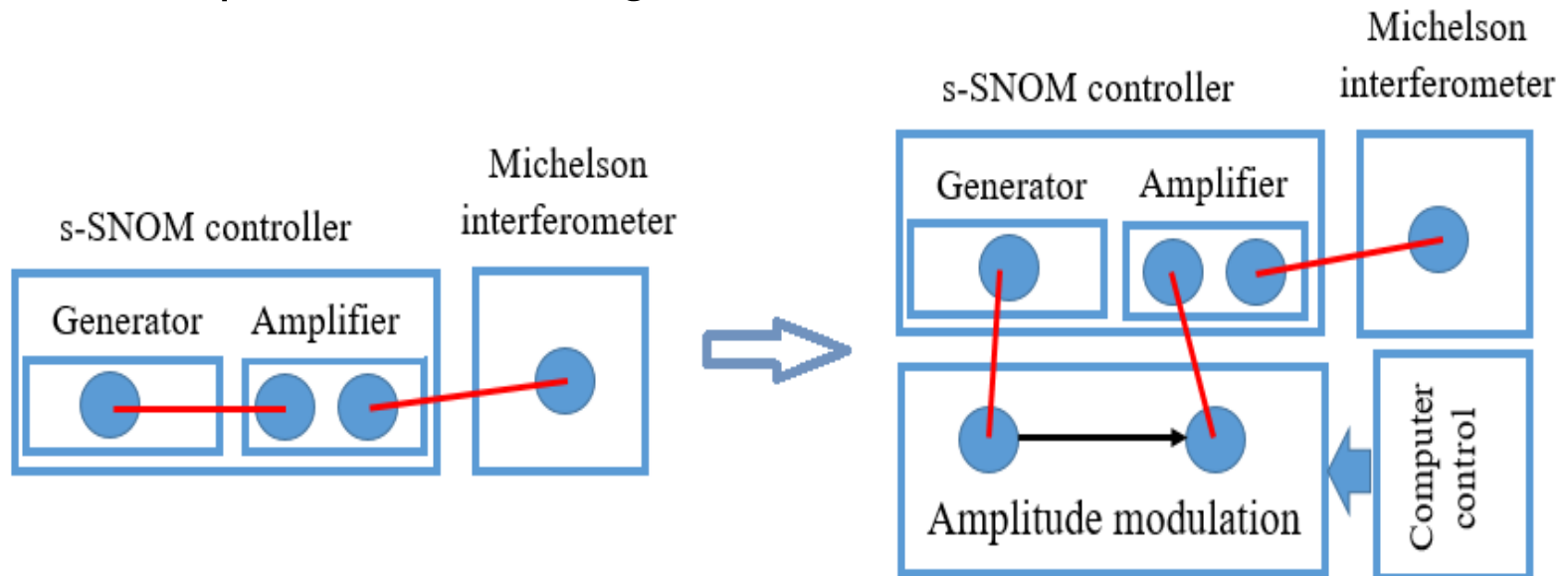
Spectroscopy with s-SNOM device

In its original setup, the s-SNOM device is a microscope
Capable of measurements on a fixed wavenumber (e.g. CNTs)

Modification for spectrum measurements

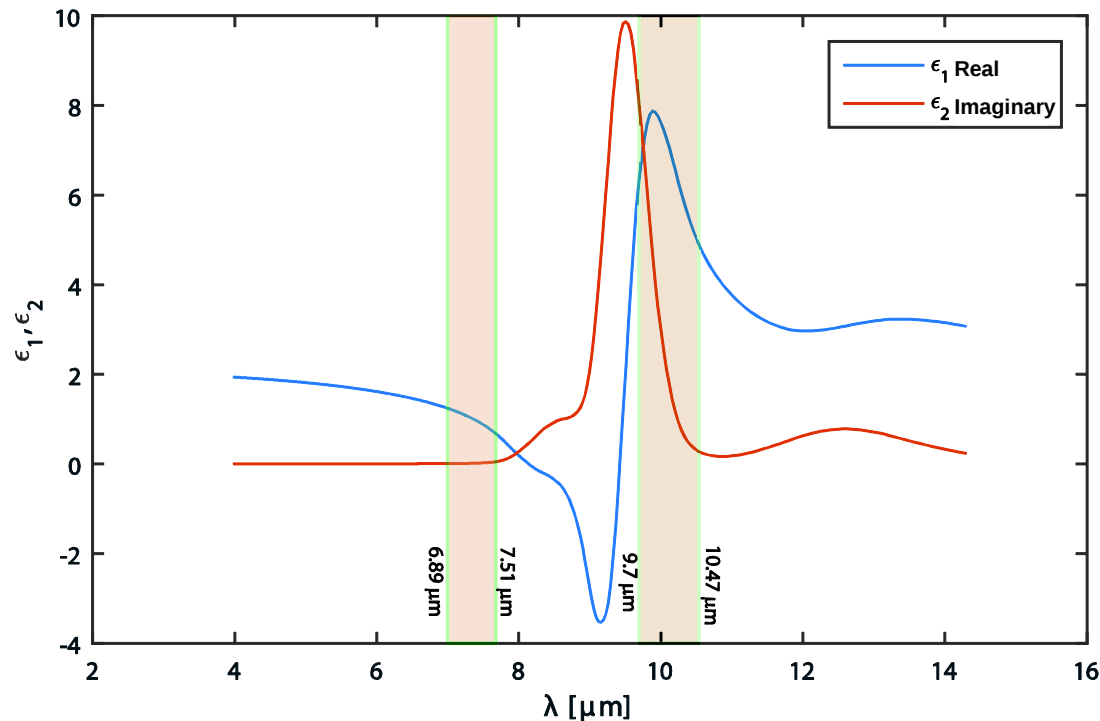
Need to set:

- wavenumber
- amplitude of vibrating mirror



Good candidates for spectroscopic measurements

- Limited spectral range due to available lasers:
- Tunable quantum cascade lasers from 950-1050 cm^{-1} and 1320-1450 cm^{-1} .



- Second laser is ideal for boron nitride.

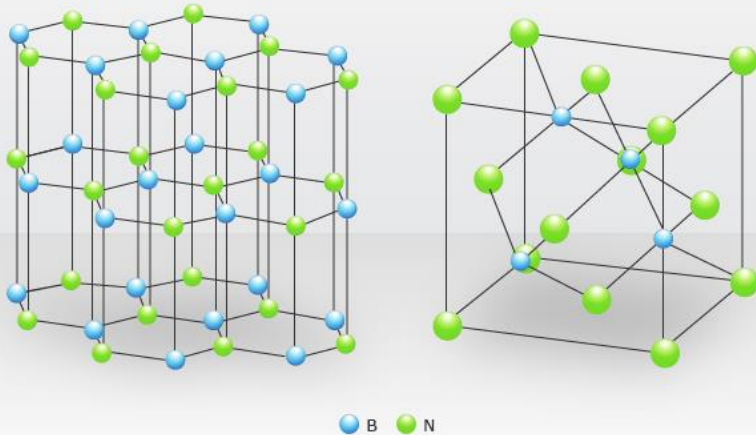
Boron nitride structures

Many different allotropes:

Boron nitride

Hexagonal boron nitride

Cubic boron nitride

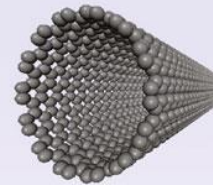


● B ● N

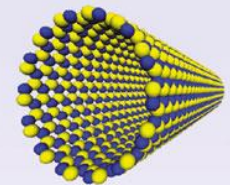
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Carbon Nanomaterials

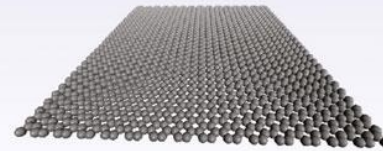
Boron Nitride Nanomaterials



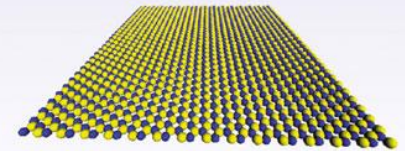
CNT



BNNT



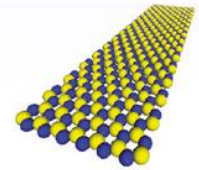
Graphene



h-BN



GNR



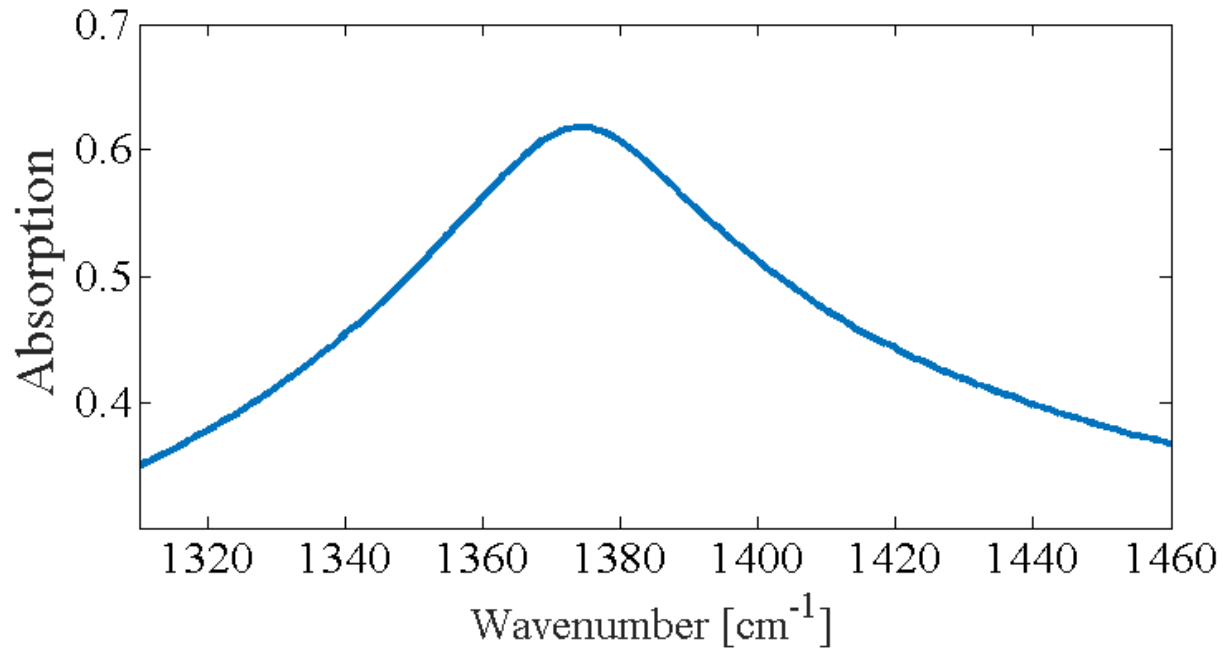
BNNR

<http://nanotechweb.org/cws/article/tech/46378>

<https://www.sciencelearn.org.nz/images/2208-boron-nitride>

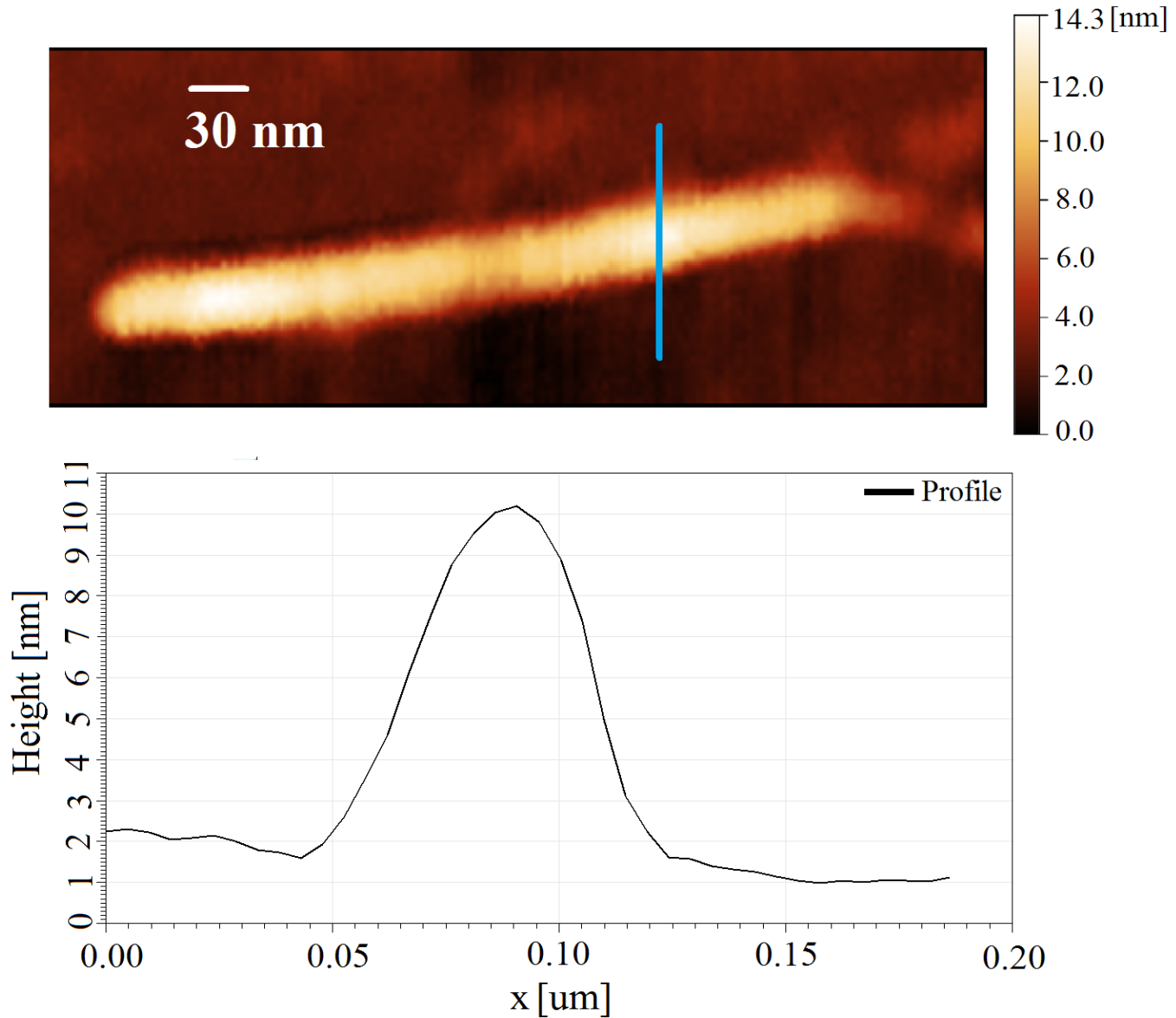
Phonon-polariton modes in BNNTs

Far-field absorption peak at 1375 cm^{-1}

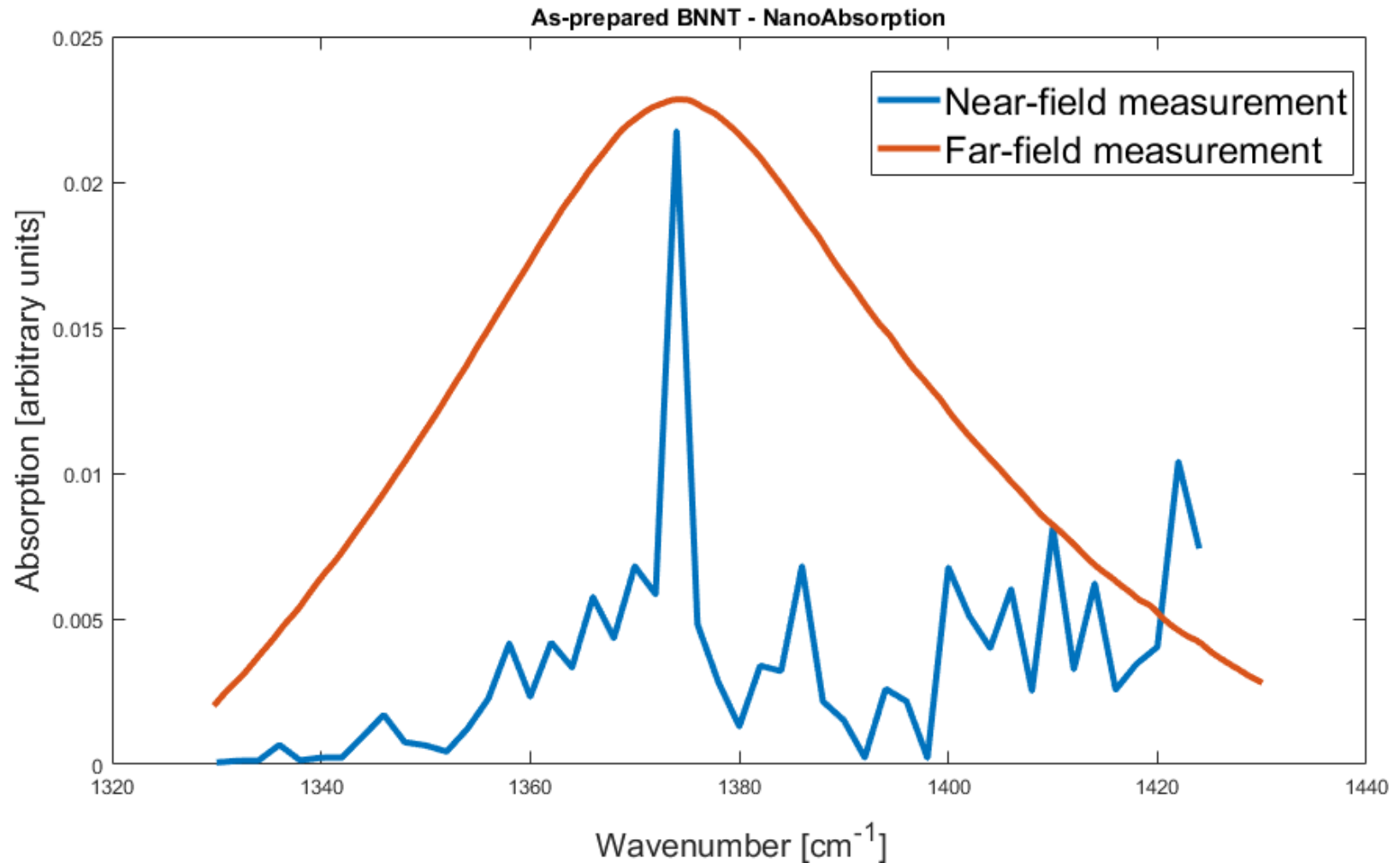


This peak corresponds to a TO mode (in-plane, longitudinal stretch).

Individual MWBNNT under AFM

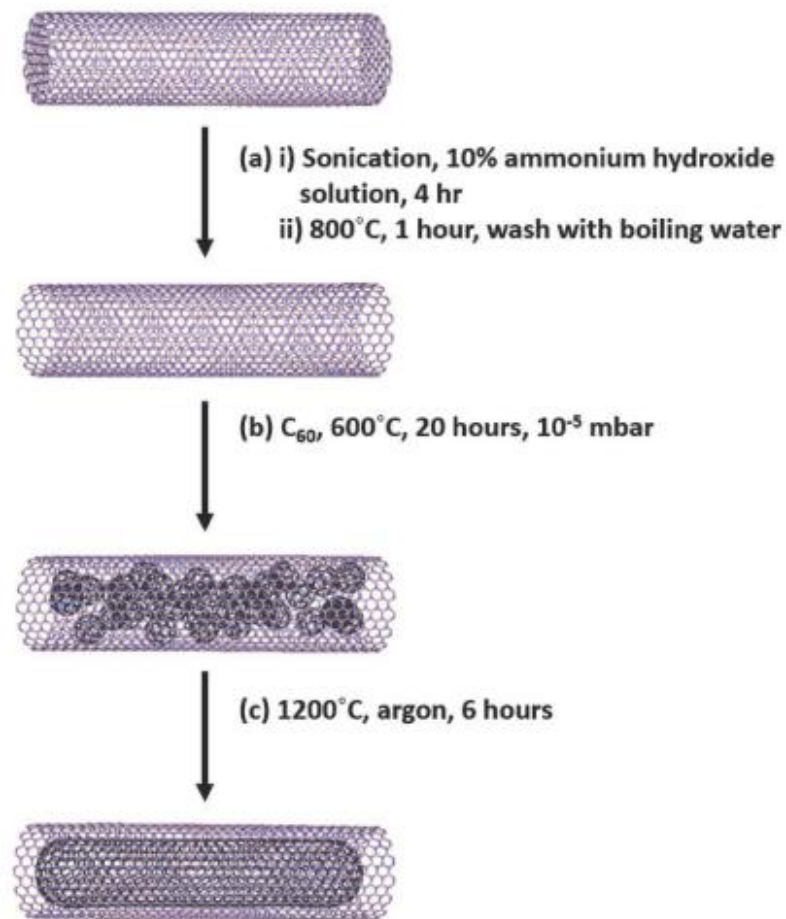
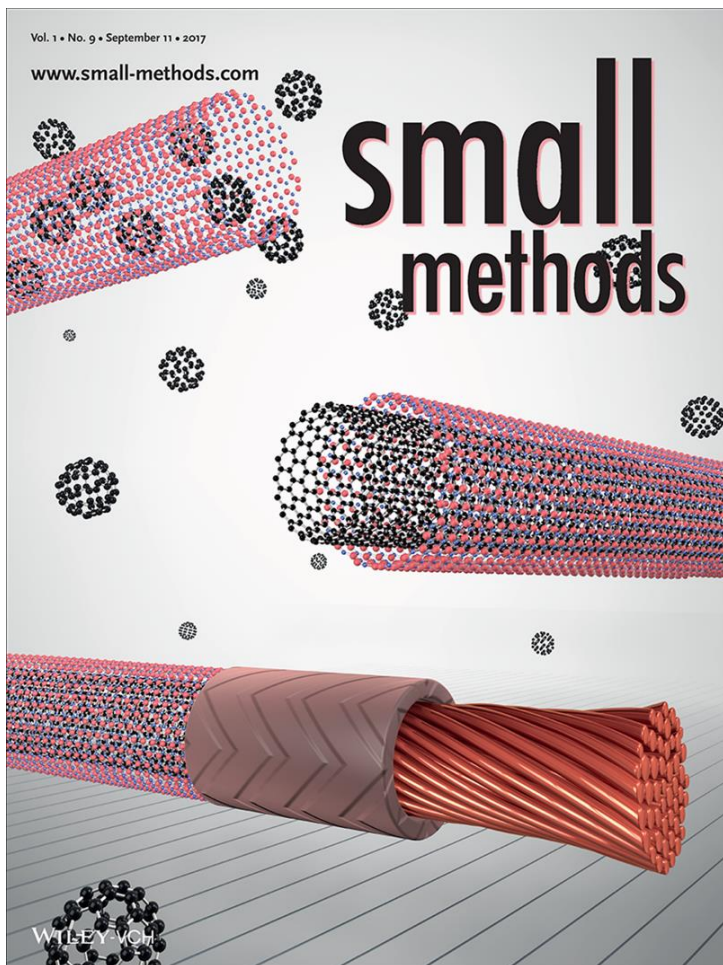


As-prepared spectrum of BNNT



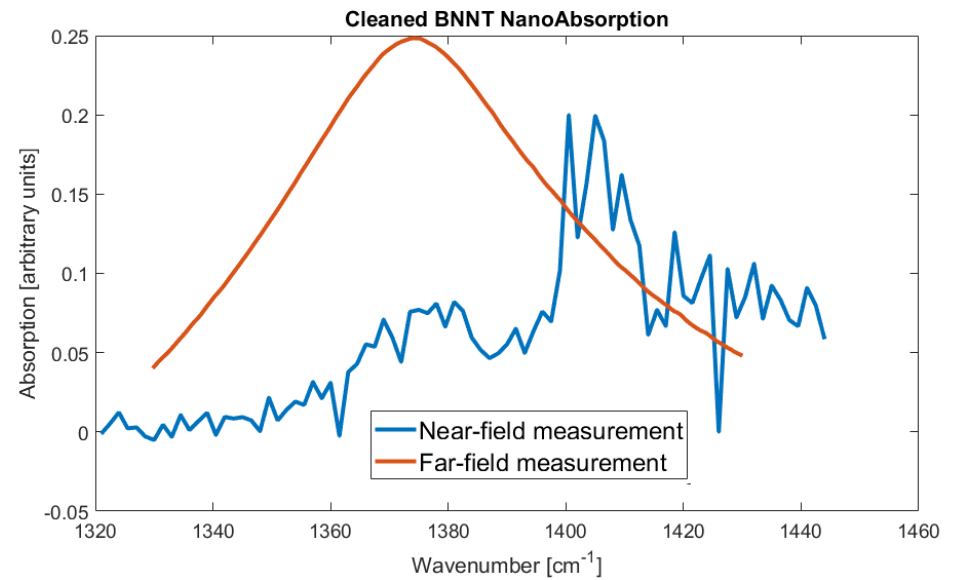
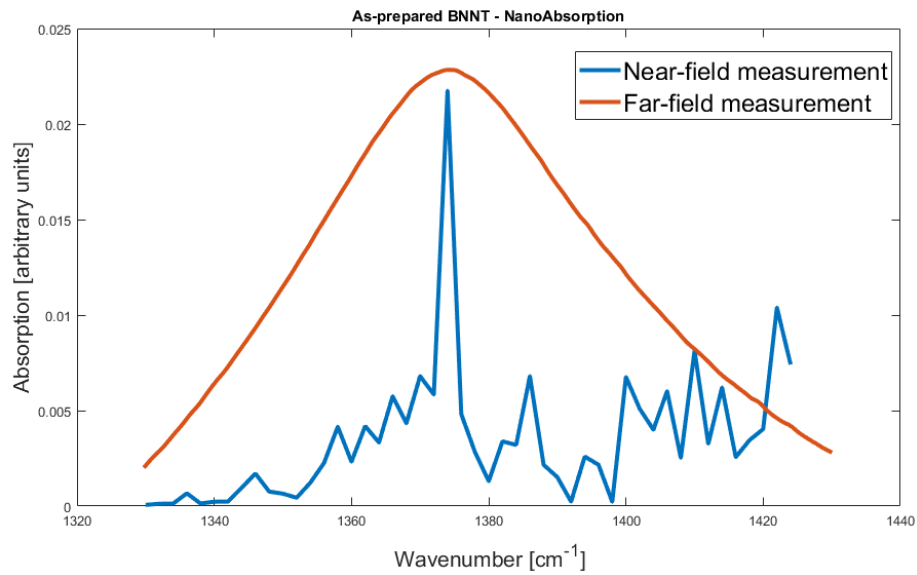
Cleaning procedure

- Opening and cleaning procedure for BNNTs
- Ultimate goal: filling with molecules

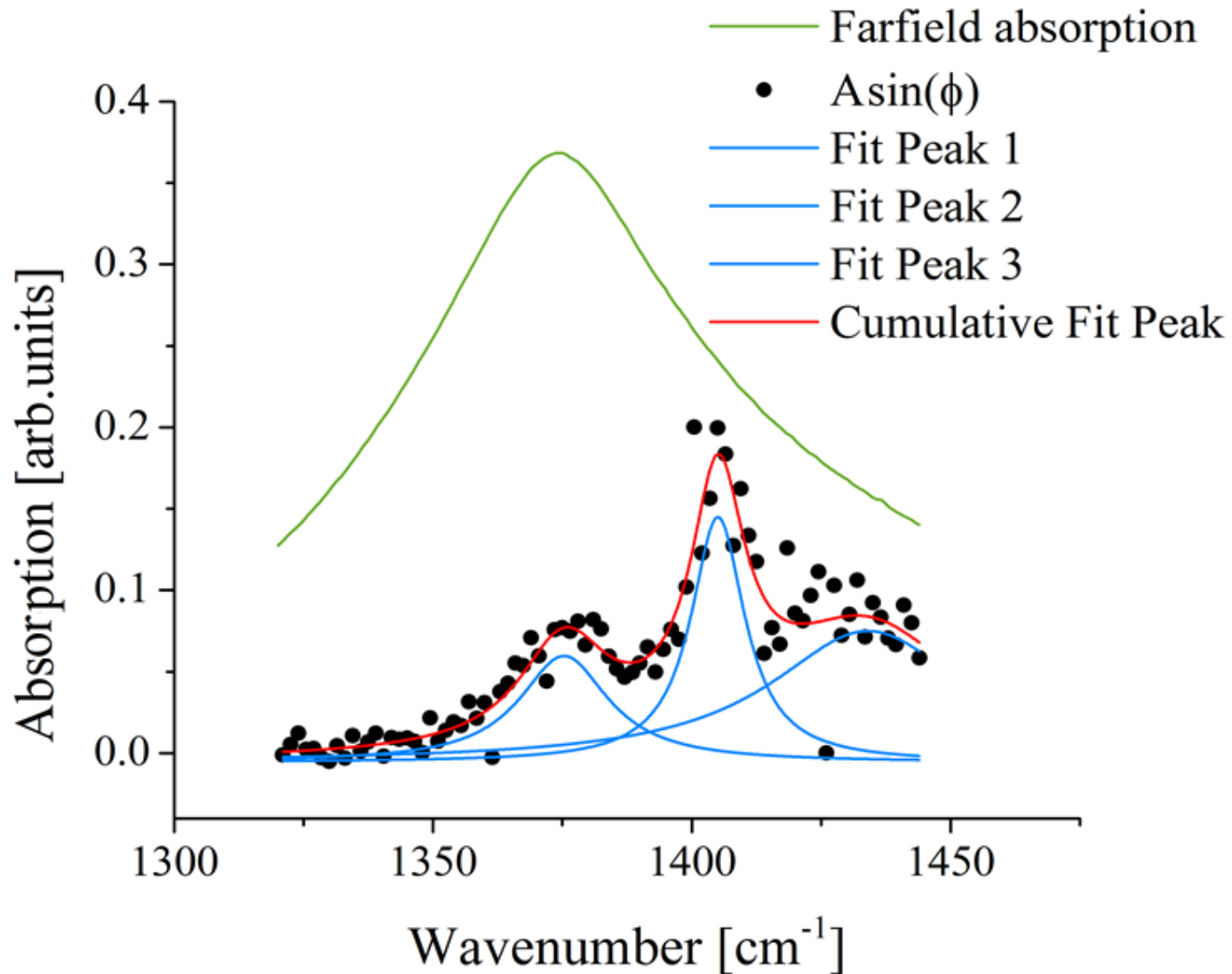


Walker, K.E., Rance, G.A., Pekker, Á., Tóháti, H.M., Fay, M.W., Lodge, R.W., Stoppiello, C.T., Kamarás, K. and Khlobystov, A.N., *Small Methods*, **1** (9), 1700184 (2017).

Absorption after cleaning



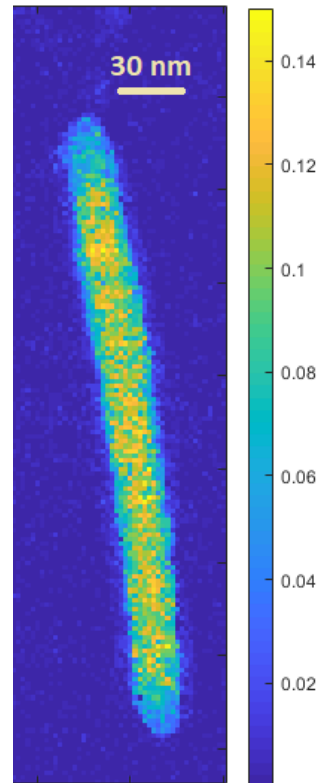
Near-field spectrum after cleaning



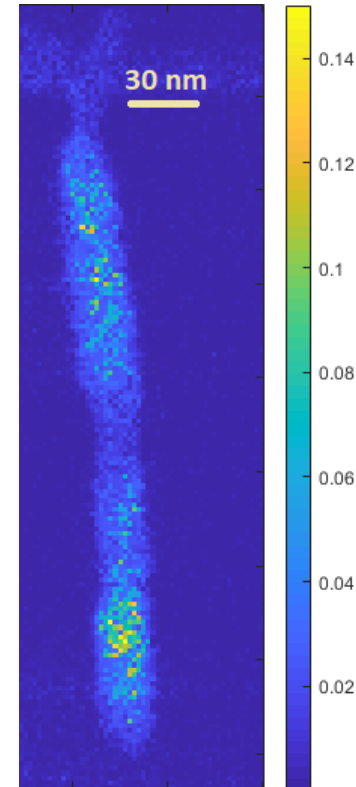
Mapping of impurities on a single nanotube

Mapping of localized phonon-polariton modes with 10 nm spatial resolution

@1380 cm^{-1}



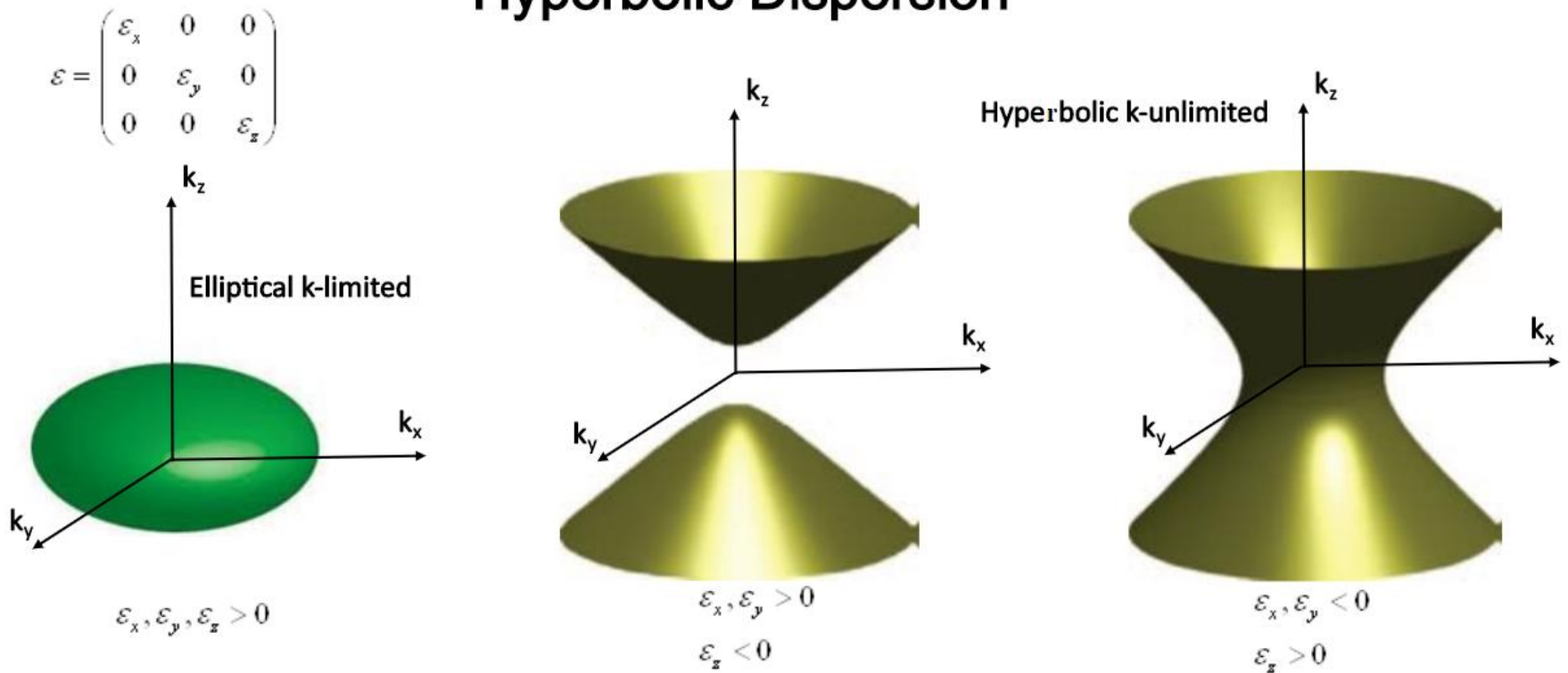
@1430 cm^{-1}



Outlook

Mapping of impurities in hBN?

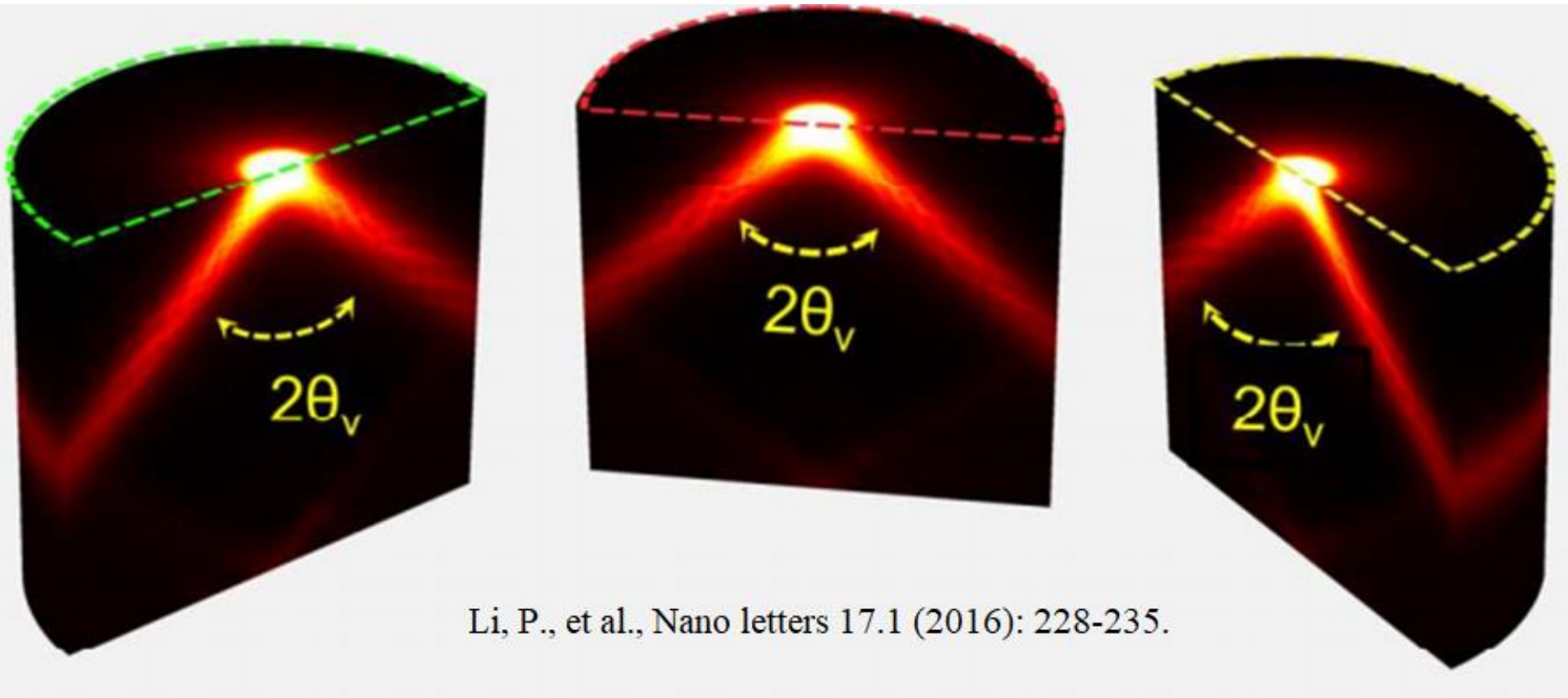
Hyperbolic Dispersion



Jacob, Z., Alekseyev, L. V. & Narimanov, E. Optical hyperlens: far-field imaging beyond the diffraction limit. *Opt. Express* **14**, 8247–8256 (2006).
Salandrino, A. & Engheta, N. Far-field subdiffraction optical microscopy using metamaterial crystals: theory and simulations. *Phys. Rev. B* **74**, 075103 (2006).

Outlook

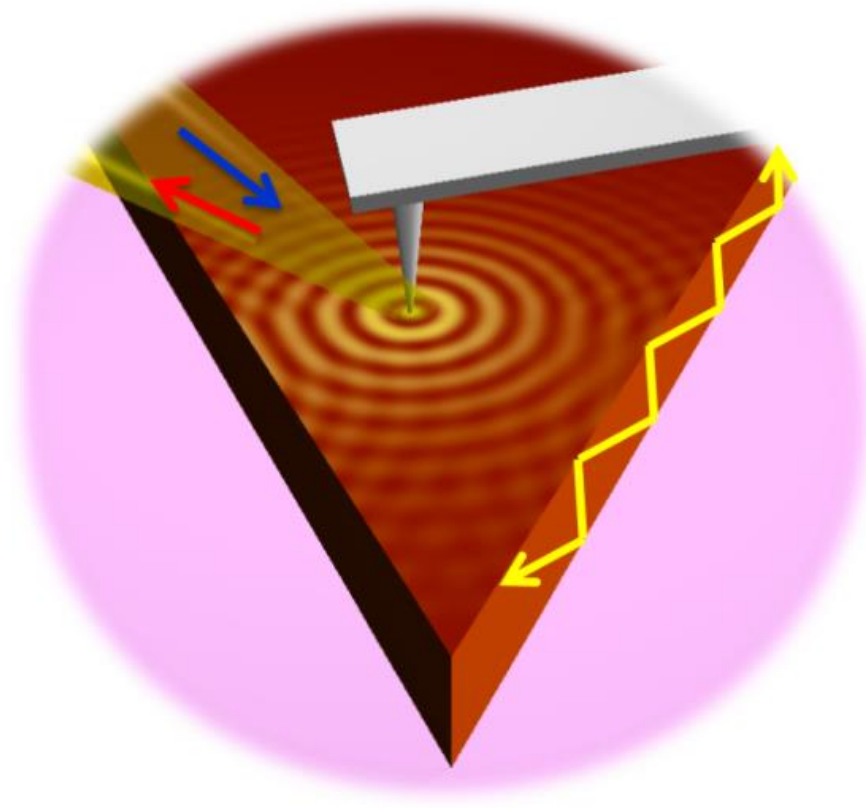
Mapping of impurities in hBN?



Li, P., et al., Nano letters 17.1 (2016): 228-235.

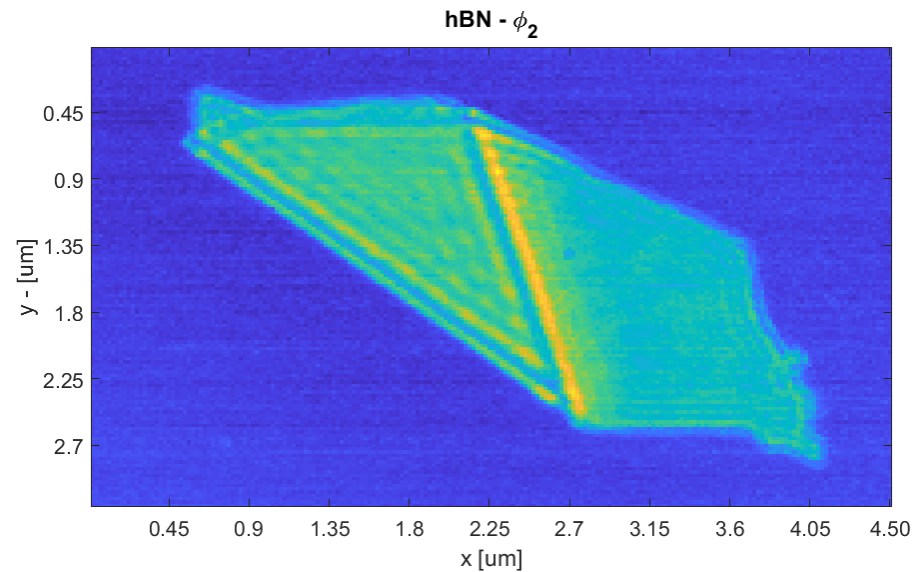
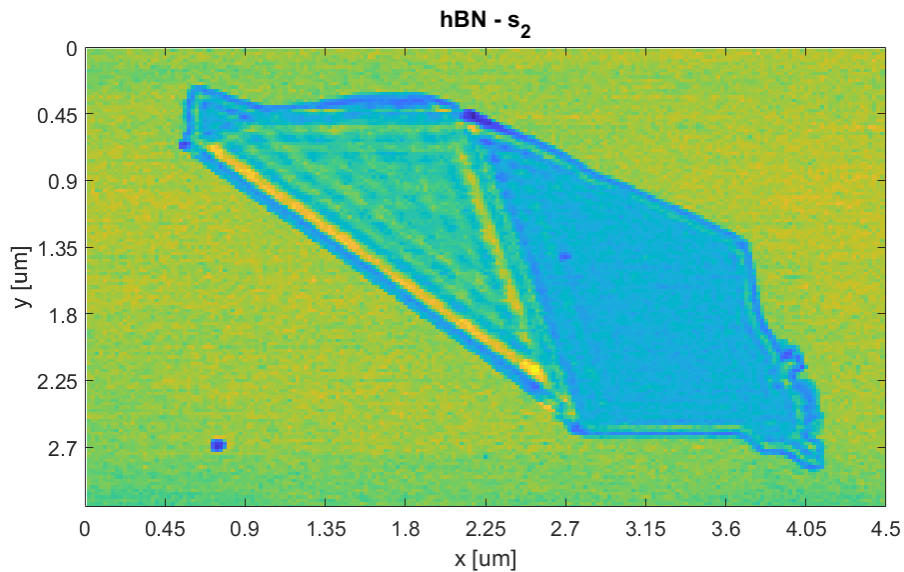
Outlook: hyperbolic phonon-polaritons

Interference patterns on edges due to reflection



Outlook: hyperbolic phonon-polaritons

Interference patterns on edges due to reflection



D. Datz unpublished